

Notice of References Cited	Application/Control No. 10/080,696		Applicant(s)/Patent Under Reexamination GOKER, TURGUY	
	Examiner Toan M Le		Art Unit 2863	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6477432	11-2002	Chen et al.	700/51
X	B	US-6556884	04-2003	Miller et al.	700/121
X	C	US-5987398	11-1999	Halverson et al.	702/179
X	D	US-6401054	06-2002	Andersen	702/179
X	E	US-6539267	03-2003	Eryurek et al.	700/51
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
X	U	"Multivariate Statistical Process Control and Signature Analysis Using Eigenfactor Detection Methods", Chen et al., the 33 rd Symposium on the Interface of Computer Science and Statistics, June 2001
X	V	"A Statistical Methods of Single and Multiple Response Surface Modeling", Smith et al., IEEE Transactions on Semiconductor Manufacturing, Vol. 12, No. 4, November 1999
X	W	"Statistical Methods for Semiconductor Manufacturing", Boning et al., Encyclopedia of Electrical Engineering, Feb. 1999
X	X	"Handbook of Statistical Methods for Engineers and Scientists", Wadsworth, Jr., McGraw-Hill, Inc., 1990

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.